

JSM-IT200: A versatile tungsten SEM

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Since 1949, JEOL's legacy has been one of the most remarkable innovations in the development of instruments used to advance scientific research and technology. JEOL has 60 years of expertise in the field of electron.

JSM-IT200 is an easy-to-use SEM focused on cost performance of high functionalities of JSM-IT500 (higher-end model) of InTouchScope™, with significantly higher throughput.

Specimen Exchange Navi, a beginner-friendly function, offers guided operation from sample loading to area search, and SEM image observation. "Zeromag" for seamless transition from optical to SEM imaging, "Live Analysis"™*2 for real time display of elemental analysis results, SMILE VIEW (TM) Lab for seamless report generation of observation and/or analysis results, etc., provide fast analysis with integrated transition from OM to SEM. Fast observation, analysis and report generation! JEOL InTouchScope™ series, the high performance analytical tool with major three functions.



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